

Integration of controlled vocabularies or ontologies in metadata schemas

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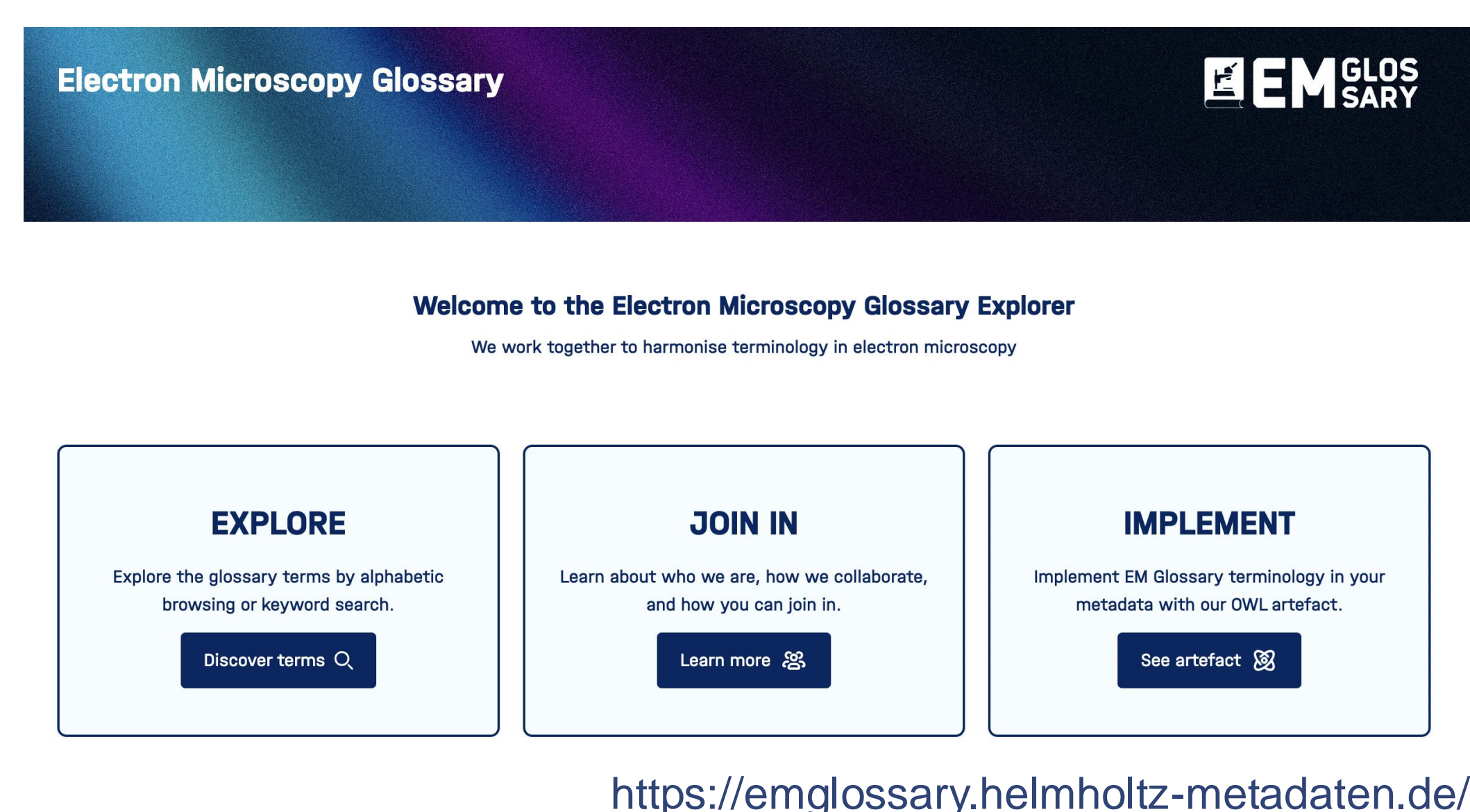
Metadata is an essential component of research data management. Metadata enhance compliance of the data with the FAIR principles. One of the most important methods for improving the quality of metadata and increasing the level of machine readability and actionability is the integration of vocabularies and ontologies in metadata (see Interoperability principle I2, <https://www.go-fair.org/fair-principles/>).



The Nanoscience Foundries and Fine Analysis (NFFA)-Europe Pilot (NEP), the Helmholtz Joint Lab “Integrated Model and Data-driven Materials Characterization” (JL-MDMC), and the National Research Data Infrastructure for Materials Science & Engineering (NFDI-MatWerk) collaboratively created the **Scanning Electron Microscopy (SEM) metadata schema**, to describe SEM images in order to facilitate data reuse and exchange.

Challenges:

- The metadata consists of hundreds of terms.
- Maintaining it is a time-consuming process.
- The FAIRness of the metadata should be increased.



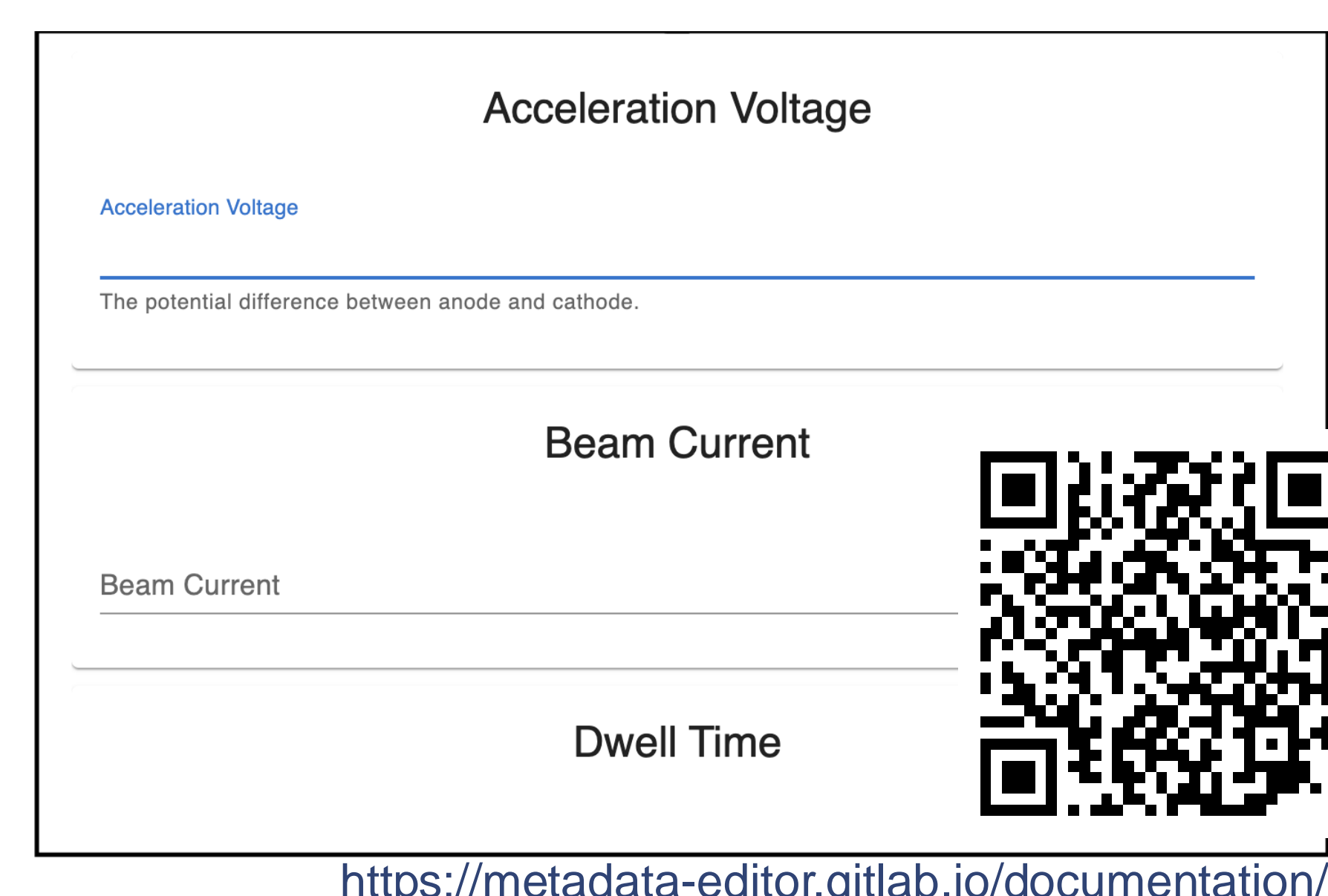
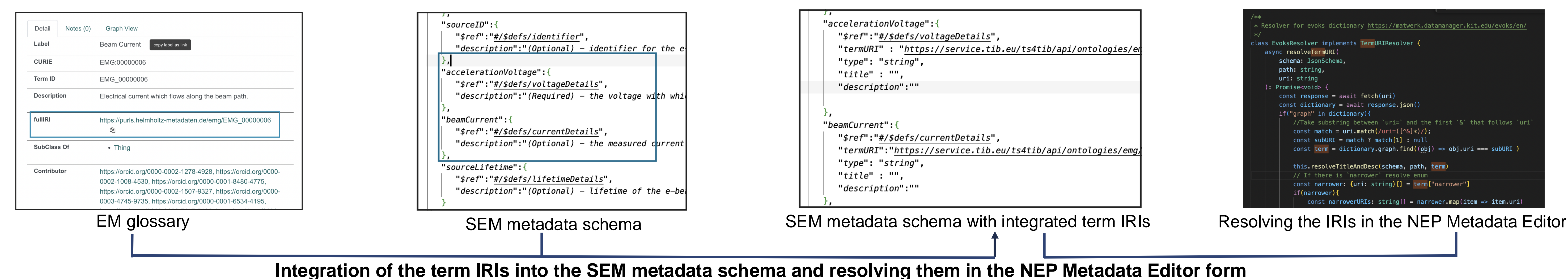
To describe the terminology and semantics of Electron Microscopy techniques at the application level, the Helmholtz Metadata Collaboration (HMC) developed the **Electron Microscopy glossary (EM glossary)** using the Web Ontology Language (OWL).

Each term of the EM glossary has an Internationalized Resource Identifier (IRI) associated to it, which allows it to be unambiguously resolved in a machine-readable way.



Integration of the EM glossary with SEM Metadata Schema

The EM glossary is registered and published in the Terminology Service (TIB). TIB provides an API through which information can be retrieved from each term using its IRI. By integrating them into the metadata schema, hard-coding of term properties is no longer required.



The Metadata Editor form automatically resolves the terms in the metadata schema and retrieves their properties (e.g., title, description, controlled list of items) from the EM glossary, supporting the user in filling the corresponding fields.

Results:

- use of controlled vocabularies and ontologies that follow FAIR principles;
- terms in schema referenced through the IRI rather than hard-coded;
- centralized maintenance of the terms;
- automatic propagation of any changes performed in the vocabulary or ontology;
- enabling the machine readability and actionability of the descriptive metadata.

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